

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/670,618	<b>FLOCK ET AL.</b>	
	<b>Examiner</b>	<b>Art Unit</b>	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner